



Product Change Notification / MFOL-04PKQY369

Date:

14-Oct-2022

Product Category:

USB Transceivers

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4630.002 Final Notice: Qualification of STA as an additional assembly site for USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package.

Affected CPNs:

[MFOL-04PKQY369_Affected_CPN_10142022.pdf](#)

[MFOL-04PKQY369_Affected_CPN_10142022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of STA as an additional assembly site for USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package.

Pre and Post Change Summary:

	Pre Change	Post Change	
Assembly Site	ASE Inc. (ASE)	ASE Inc. (ASE)	STATS Chippac Ltd. (STA)
Wire Material	CuPd	CuPd	CuPdAu
Die Attach Material	EN-4900F	EN-4900F	8290
Molding Compound Material	G631B	G631B	G700E
Lead-Frame Material	C194	C194	C194
Lead-Frame Paddle Size	138X138 mils	138X138 mils	138X138 mils
DAP Surface Prep	Double Ring Plating	Double Ring Plating	Ring Plating
	See Pre and Post Change Summary for comparison.		

Impacts to Data Sheet:None

Change Impact:None

Reason for Change:To improve on-time delivery performance by qualifying STA as an additional assembly site.

Change Implementation Status:In Progress

Estimated First Ship Date:November 16, 2022 (date code: 2247)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	October 2022					November 2022				
Workweek	4 0	4 1	4 2	4 3	4 4	4 5	4 6	4 7	4 8	4 9
Qual Report Availability		x								
Final PCN Issue Date		x								
Estimated Implementation Date								x		

Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

October 06, 2022: Issued final notification.

October 14, 2022: Re-issued final notification to remove the tray comparison drawing in pre and post change summary.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_MFOL-04PKQY369 Pre and Post Change Summary.pdf](#)

[PCN_MFOL-04PKQY369_Qual Report.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

MFOL-04PKQY369 - CCB 4630.002 Final Notice: Qualification of STA as an additional assembly site for USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package.

Affected Catalog Part Numbers (CPN)

USB3340-EZK

USB3340-EZK-TR

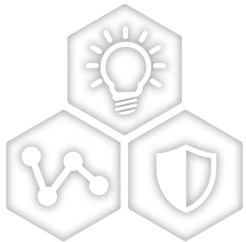
USB3370B-EZK

USB3370B-EZK-TR

CCB 4630.002
Pre and Post Change Summary
PCN# MFOL-04PKQY369



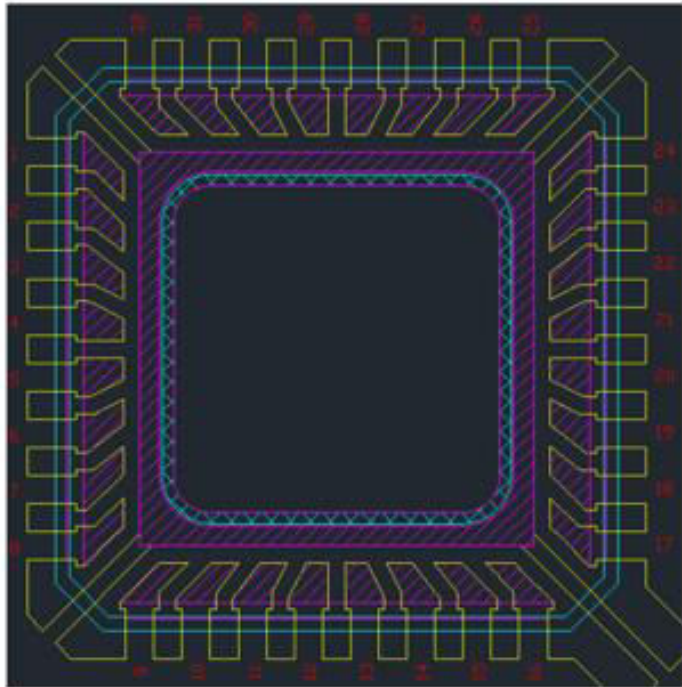
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

Lead Frame Comparison

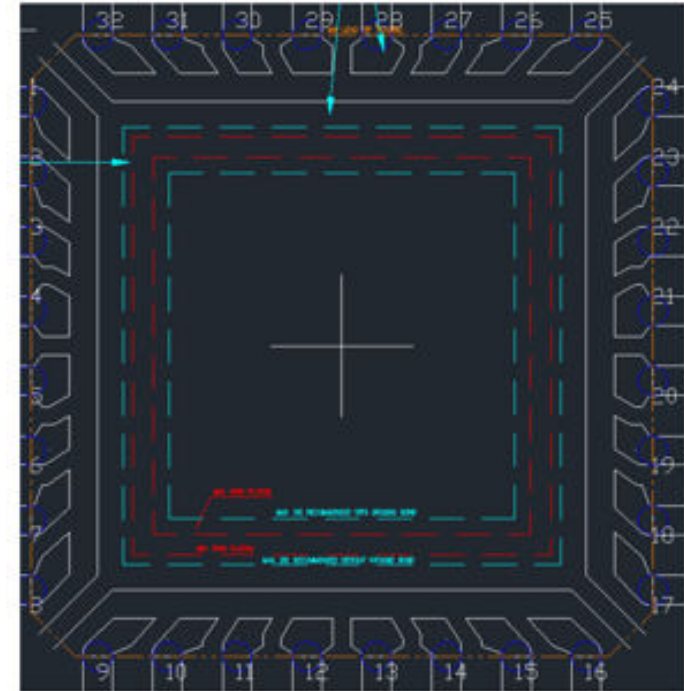
ASE



Lead frame
material

C194

STA



Lead frame
material

C194



MICROCHIP

**QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY**

PCN ID#: MFOL-04PKQY369

**Date:
November 2, 2021**

Qualification of STA as an additional assembly site for selected LAN9303, LAN9210 and LAN9211 device families available in 56L VQFN (8x8x0.9mm) package. The selected USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package will qualify by similarity (QBS).



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose	Qualification of STA as an additional assembly site for selected LAN9303, LAN9210 and LAN9211 device families available in 56L VQFN (8x8x0.9mm) package. The selected USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package will qualify by similarity (QBS).
CCB	4630.002 and 4630
CN	ES361355
QUAL ID	R2100817 REV. A
MP CODE	TA3017RTXB0C
Part No.	LAN9303I-ABZJ
Bonding No.	BDM-002969 Rev. A
<u>Package</u>	
Type	56L VQFN
Package size	8 x 8 x 0.9 mm
<u>Lead Frame</u>	
Paddle size	236 x 236 mils
Material	C194
Surface	Double Ring
Process	Etched
Lead Lock	No
Part Number	R002-3646X
<u>Material</u>	
Epoxy	8290
Wire	CuPdAu wire
Mold Compound	G700E
Plating Composition	Matte Sn



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
STA-221300006.000	TC11922050505.100	2125YMV
STA-221300008.000	TC11922050505.100	2125YPR
STA-221300007.000	TC11922050505.100	2125YPH

Result

Pass Fail

56L VQFN (8x8x0.9 mm) assembled by STA pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C
reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test: +25°C and 100°C System: EX_ANALOG Bake 150°C, 24 hrs System: CHINEE 30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 Electrical Test: +25°C and 100°C System: EX_ANALOG	JESD22- A113 JIP/ IPC/JEDEC J-STD-020E	693(0)	693 693 693 0/693	Pass	Good Devices

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +100°C System: EX_ANALOG	JESD22- A104		231		Parts had been pre-conditioned at 260°C 77 units / lot
	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +100°C System: EX_ANALOG		231(0)	0/231	Pass	
	Bond Strength: Wire Pull (> 2.50 grams) Bond Shear (>12.60 grams)		15 (0)	0/15	Pass	
			15 (0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: EX_ANALOG	JESD22- A118		231		Parts had been pre-conditioned at 260°C 77 units / lot
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X Electrical Test: +25°C System: EX_ANALOG		231(0)	0/231	Pass	
			231(0)	0/231	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22-A103		45		45 units
	Electrical Test: +25°C and 100°C System: EX_ANALOG		45(0)	0/45	Pass	
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22 22 0/22	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (> 3.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass	
	Bond Shear (> 8.00 grams)	CDF-AEC-Q100-001	30 (0) bonds	0/30	Pass	